

**Notice of References Cited**

Application/Control No.

10/052,921

Applicant(s)/Patent Under  
Reexamination  
LI ET AL.

Examiner

Kaj K Olsen

Art Unit

1753

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**NON-PATENT DOCUMENTS**

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	W	Gyurcsanyi et al, Anal. Chem., 05-2001, 73(9), pp. 2104-2111.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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